

Notice of References Cited	Application/Control No. 10/575,387		Applicant(s)/Patent Under Reexamination GAWEL ET AL.	
	Examiner SENG H. LIM		Art Unit 3714	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,102,394 A	08-2000	Wurz et al.	273/138.2
*	B	US-6,227,970 B1	05-2001	Shimizu et al.	463/20
*	C	US-6,311,974 B1	11-2001	Koga, Akira	273/118R
*	D	US-6,475,087 B1	11-2002	Cole, Joseph	463/20
*	E	US-2003/0224853 A1	12-2003	Guindulain Vidondo, Felix	463/20
*	F	US-2003/0222402 A1	12-2003	Olive, Scott	273/292
*	G	US-6,659,867 B1	12-2003	Kodachi et al.	463/20
*	H	US-2004/0018870 A1	01-2004	Cole, Joseph W.	463/20
*	I	US-2004/0061284 A1	04-2004	Satoh, Masatoshi	273/138.1
*	J	US-2004/0162132 A1	08-2004	Jaffe et al.	463/020
*	K	US-2004/0198485 A1	10-2004	Loose et al.	463/020
*	L	US-2009/0325680 A1	12-2009	TSUKABE, Shinji	463/20
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.